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Transient Techniques for Battery Impedance Measurements

Small-Amplitude Exponential Perturbation Technique

Prepared by

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1 July 1981

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This technical report has been reviewed and is approved for publication. Publication of this report does not constitute Air Force approval of the report's findings or conclusions. It is published only for the exchange and stimulation of ideas.

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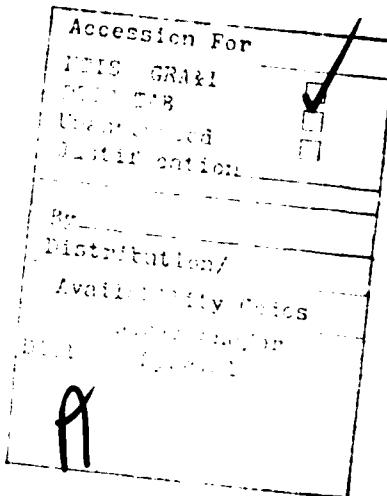
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20. ABSTRACT (Continue on reverse side if necessary and identify by block number) A perturbation technique is reported for measuring the impedance of battery cells under conditions of controlled potential. The small amplitude exponential perturbation (SAEP) technique is applicable over an extremely wide frequency range and appears to be the method of choice for measuring the impedance of battery cells that contain very little stored electrochemical energy.		

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I. INTRODUCTION

The proper operation of battery cells invariably depends on a number of internal physical and chemical reactions occurring at rates that are sufficient to sustain cell performance. These reactions typically involve charge transfer processes at the electrodes, as well as diffusional transport of materials to the active electrode surfaces. Kinetic measurements permit determination of the relative importance of these processes in controlling cell performance. The most general method for making these kinetic measurements is to measure the electrical impedance of the battery cell as a function of frequency. The rates of the various processes that affect the cell voltage are inferred directly from the frequency dispersion of the cell impedance.

A number of techniques have been used to measure the impedance of battery cells. The most commonly used is that of applying a sinusoidally varying ac signal to the battery cell and monitoring the cell response in terms of amplitude and ac phase shift. This ac method is relatively easy to use, but if data are required over a wide frequency range or at very low frequencies, it becomes somewhat cumbersome. Other techniques for impedance measurements of battery cells incorporate perturbing functions other than sinusoidal ac. For example, in the galvanostatic transient technique¹ a step change in the current passing through the cell is applied, and the response of the cell to the current change is measured. The relationship between the change in cell current and the voltage response gives the cell impedance. This technique is particularly useful when the cell contains appreciable stored capacity, since in this case controlling cell current is much easier than controlling cell voltage. However, when the cell contains very little stored capacity, any measurement attempted under conditions of constant current may change the cell voltage by a large amount and thereby appreciably alter the chemical state of the cell. In this situation, it is desirable to employ a potentiostatic

¹A. H. Zimmerman and M. R. Martinelli, Transient Techniques for Low Frequency Impedance Measurements, TR-0079(4970-10)-1, The Aerospace Corporation, El Segundo, Calif (6 October 1978).

technique that involves the application of a controlled perturbation to the cell potential.

We have developed and applied such a technique to battery cells. This technique is called small amplitude exponential perturbation (SAEP) and involves perturbing the cell voltage with a small amplitude (<5 mV) exponential signal while measuring the current response of the cell. Again, the cell impedance is obtained from the relationship between voltage and current. This technique can be used to measure the impedance of battery cells at any voltage or state of charge that is accessible to them, although very large currents (and power supplies) may be involved when the cell has appreciable active electrochemical capacity.

II. THEORY OF SAEP

Any potentiostatic transient technique for measuring impedance employs a transient potential function $V(t)$. This potential function is applied as a perturbation to a battery cell that has the initial potential V_0 . The cell current is initially $I_0 + I_N(t)$, where I_0 is the steady-state current at V_0 , and $I_N(t)$ is any change in current resulting from depletion of the stored electrochemical capacity of the cell at the initial voltage. After the perturbation $V(t)$ is applied, the current is $I_0 + I_N(t) + I(t)$. For this analysis to be correct, the amplitude of $V(t)$ must be sufficiently small that $I_N(t)$ does not change appreciably in response to $V(t)$. This means that typically $V(t)$ should be less than 5 mV in amplitude. In addition, the time constant associated with $I_N(t)$ must be much greater than that associated with $I(t)$ so that they can be separated in time.

The impedance as a function of time is then directly given by Ohm's law

$$Z(t) = \frac{V(t)}{I(t)} \quad (1)$$

However, the cell impedance is more conveniently analyzed in the frequency domain. Laplace transformation of $V(t)$ and $I(t)$ permits us to obtain the impedance as a function of frequency.

$$Z(\omega) = \frac{V(\omega)}{I(\omega)} \quad (2)$$

where $V(\omega)$ and $I(\omega)$ are the Laplace transforms of voltage and current, respectively.

The digital Laplace transforms required are calculated from the voltage and current data,

$$F(\omega) = \int_0^\infty f(t) \exp(-j\omega t) dt = \sum_i \int_{t_i}^{t_{i+1}} f_i(t) \exp(-j\omega t) dt \quad (3)$$

which are digitized by computer into arrays having i data points, each corresponding to a given time. The function $f_i(t)$ fits the data for $f(t)$ in the interval t_i to t_{i+1} and may be any convenient function that fits the data. Functions used for $f(t)$ include linear, quadratic, and exponential forms as follows.

1. Linear: $f_i(t) = A_i t + B_i$

$$A_i = \frac{f(t_i) - B_i}{t_i}$$

$$B_i = \frac{[f(t_{i+1}) - t_{i+1}/t_i f(t_i)]}{1 - \frac{t_{i+1}}{t_i}} \quad (4)$$

2. Quadratic: $f_i(t) = L_i t^2 + M_i t + N_i$

$$M_i = [\frac{\Delta f_{12}}{\Delta t_{12}^2} (\frac{t_1^2}{t_{i+2}} - t_{i+2}) - \frac{\Delta f_{13}}{t_{i+2}}] [1 - (t_{i+2}) \frac{\Delta t_{12}}{\Delta t_{12}^2} + \frac{t_i}{t_{i+2}} (\frac{t_i \Delta t_{12}}{\Delta t_{12}^2} - 1)]^{-1}$$

$$L_i = \frac{\Delta f_{12}}{\Delta t_{12}^2} - M_i (\frac{\Delta t_{12}}{\Delta t_{12}^2}) \quad (5)$$

$$N_i = f(t_i) - L_i t_i^2 - M_i t_i$$

where

$$\Delta t_{12} = t_i - t_{i+1}$$

$$\Delta t_{12}^2 = t_i^2 - t_{i+1}^2$$

$$\Delta f_{12} = f(t_i) - f(t_{i+1})$$

$$\Delta f_{13} = f(t_i) - f(t_{i+2})$$

3. Exponential:

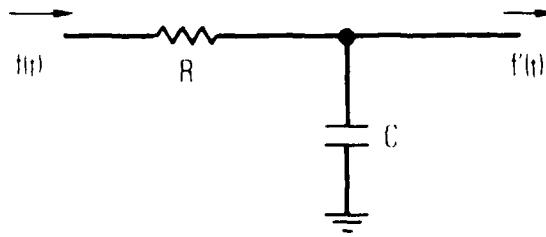
$$f_i(t) = C_i \exp(-a_i t) \quad (6)$$

$$a_i = \ln \left[\frac{f(t_{i+1})/f(t_i)}{t_i - t_{i+1}} \right]$$

$$C_i = f(t_i) \exp(a_i t_i)$$

The exponential function of Eq. (6) gave the best results for all data that were not near a point where $f(t)$ crossed zero. A listing of a Fortran program for doing the transformations that give the impedance is provided in the Appendix.

Actual experimental data contain noise; in particular, 60-Hz noise may pose a problem when small changes in voltage or current are being monitored. The simplest way to eliminate this kind of noise is with an RC filter.



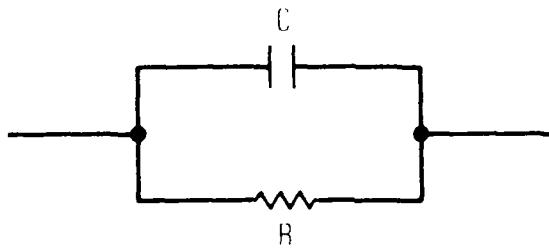
However, the transfer function of this filter must then be deconvoluted from the data. This is easily done in the frequency domain simply by multiplying the transformed function by the inverse filter function transform

$$f(\omega) = f'(\omega) (1 + j\omega\tau_F) \quad (7)$$

where $\tau_F = RC$ is the filter time constant.

III. RESULTS

The impedance of battery cells below 1 kHz is generally capacitive in nature, behaving as an equivalent parallel RC circuit where the values of R and C may have a complicated dependence on frequency. The results of an SAEP experiment on a simple dummy cell consisting of the RC circuit



where $C = 1 \text{ F}$ and $R = 10 \Omega$ are examined first. For simplicity, let us assume that $V_0 + V_N(t)$, the initial cell voltage, is zero. An increasing exponential perturbation having amplitude α and time constant τ is applied to the cell

$$V(t) = \alpha(1 - e^{-t/\tau}) \quad (8)$$

$V(t)$ and the current response of the dummy cell $I(t)$ are indicated in Fig. 1 for $\tau = 2\text{s}$, $R = 10 \Omega$, and $C = 1 \text{ F}$. $I(t)$ is given by the relationship

$$I(t) = \frac{\alpha}{R} \left[1 - \left(1 - \frac{RC}{\tau}\right) e^{-t/\tau} \right] \quad (9)$$

Note that the values of R and C do not influence the time constant for current decay, but only control the amplitude of the current transient. From the time-dependent voltage and current functions, the impedance is calculated, with the results shown in Fig. 2 in the complex plane. The results in Fig. 2 agree with the theoretical result for the impedance

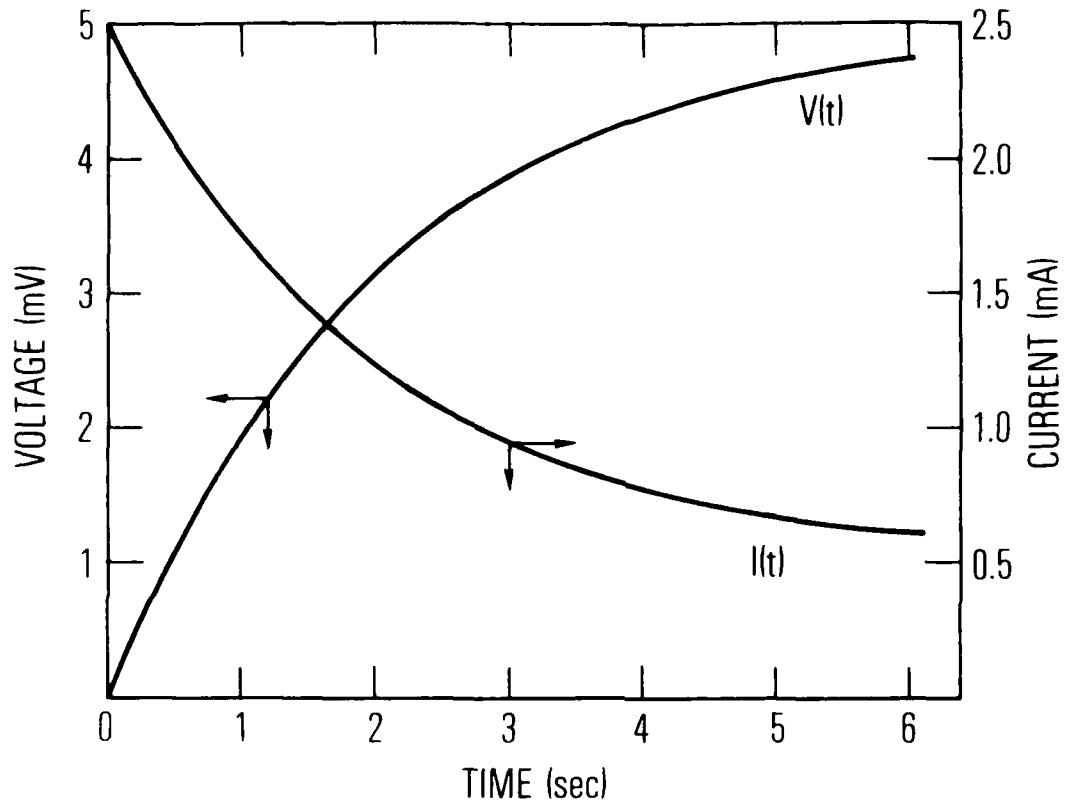


Fig. 1. Voltage Perturbation and Response Current for Dummy Cell

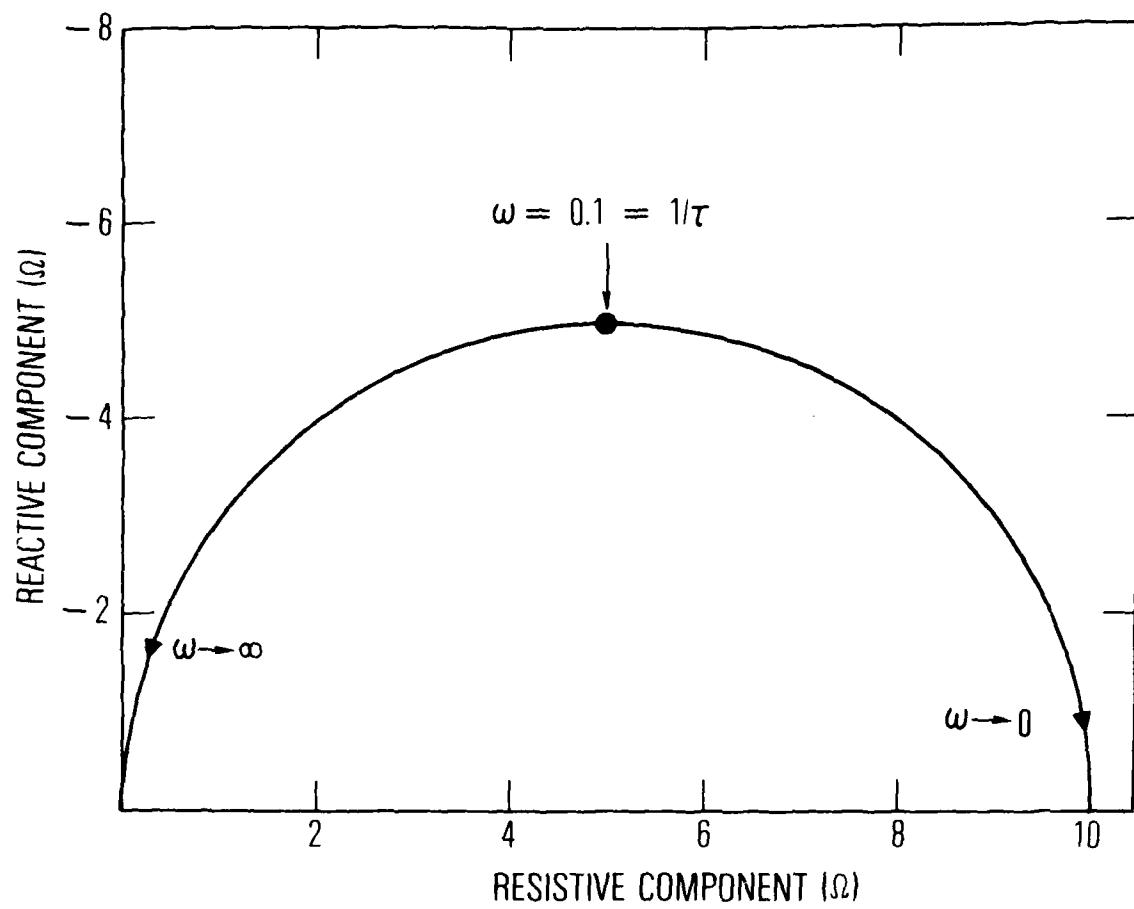


Fig. 2. Impedance of Dummy Cell from Data of Fig. 1

$$Z(\omega) = \frac{R}{1 + j\omega RC} \quad (10)$$

This simple example illustrates that the expected current response for a battery cell consists of a rapid rise to a maximum, followed by a decay to a steady-state current that is different from the initial current by the amount α/R . The magnitude of the peak current is controlled by the relative time constants of the exponential perturbation and the cell, and is given by $\alpha C/\tau$ in the preceding example. Thus, the experimental maximum transient current can be controlled simply by controlling the perturbation time constant.

The results obtained when an exponential perturbation is applied to a nickel cadmium cell are shown in Fig. 3. The nickel cadmium cell used was a 10-Ah prismatic cell, and the initial cell voltage was 0.5 V. The impedance is indicated in the complex plane in Fig. 4. In making these measurements, it was found that signal to noise became relatively poor unless the time constant of the applied perturbation was the same order of magnitude as the relaxation time for the battery cell. With this general requirement satisfied, the SAEP technique provides a convenient method for making impedance measurements on battery cells over an extremely wide range of frequencies, under conditions of battery operation for which potential control is acceptable.

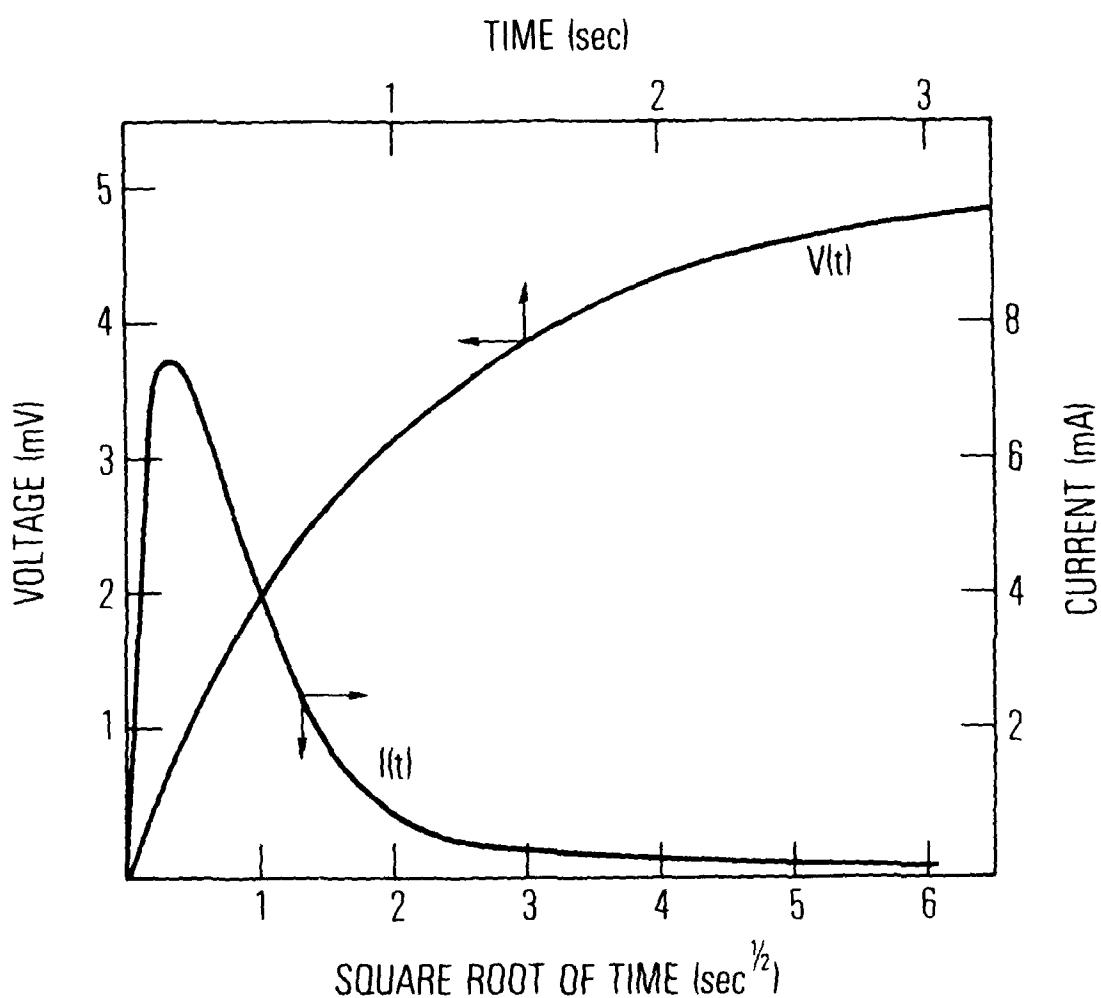


Fig. 3. Voltage Perturbation and Current Response for Nickel Cadmium Cell at 0.5 V

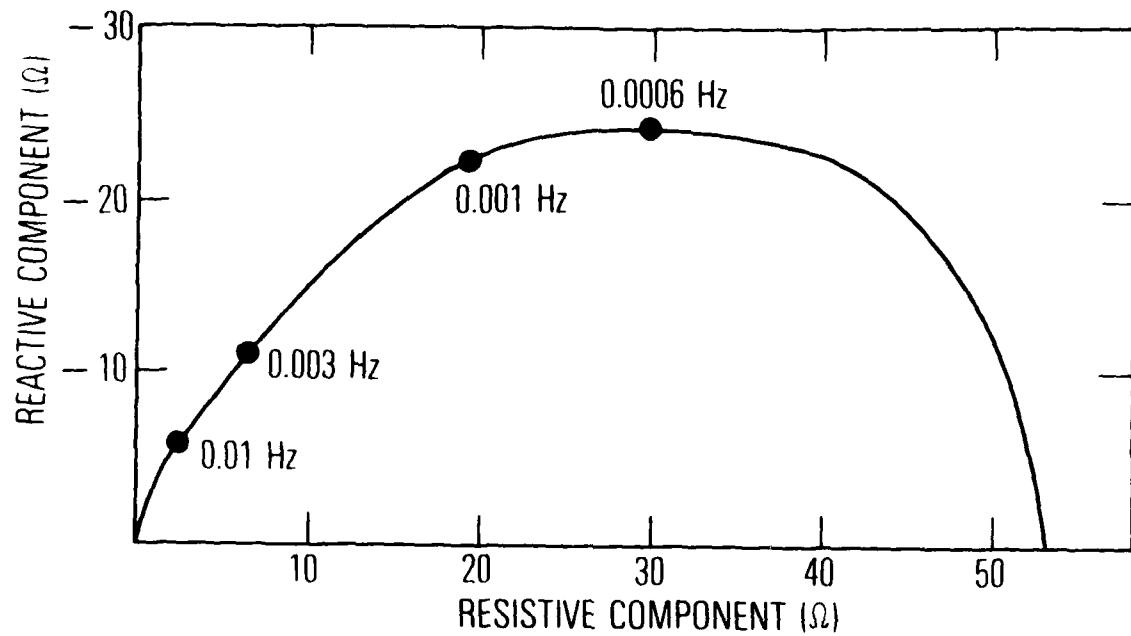


Fig. 4. Impedance of Nickel Cadmium Cell from Data of Fig. 3

IV. CONCLUSIONS

The SAEP technique has been developed and applied to measuring the impedance of battery cells under conditions of controlled potential. This appears to be the optimum method for measuring the impedance of battery cells that contain little stored electrochemical capacity.

APPENDIX

FORTRAN PROGRAM FOR SAEP IMPEDANCE CALCULATION

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PROGRAM SAEP1 INPUT, OUT1UT, TAPES=OUTPUT) FREQUENCY FROM THIS PROGRAM CALCULATES IMPEDANCE AS A FUNCTION OF FREQUENCY FROM AN EXPONENTIAL VOLTAGE PERTURBATION AND ITS CURRENT RESPONSE USING THE LAPLACE TRANSFORMATION TECHNIQUE. THE FILTER FUNCTION MAY BE INCLUDED IN THE CURRENT RESPONSE, AND IS DECONVOLUTED FROM THE TRANSFORM.

THE PROGRAM FITS THE DATA TO A MAXIMUM OF TWO DIFFUSION PROCESSES. IT REQUIRES INITIAL GUESSES FOR THE FITTING PARAMETERS WHICH ARE TIME CONSTANTS α_1 AND α_2 , WARBURG COEFFICIENTS S_1 AND S_2 , AND CAPACITANCES C_1 AND C_2 AS WELL AS ELECTROLYTE RESISTANCE R_Z .

DATA INPUTS ARE IDENTIFICATION NUMBER
 M_{PROB} = EXPFITMENT OF VOLTAGE DATA POINTS
 N_{DATA} = NUMBER OF CURRENT DATA POINTS
 $TSAEP$ = NOMINAL PERTURBATION TIME CONSTANT IN SECONDS
 A_{MPV} = AMPLITUDE OF EXPONENTIALLY CHANGED AT INFINITE TIME IN MA
 $FILTC$ = FILTER CONSTANT OF CURRENT FOR VOLTAGE/TIME DATA (SEC)
 $FILT$ = TIME CONSTANT OF FILTER USED FOR VOLTAGE/TIME DATA (SEC) AND
 $VV(I)$, $XI(I)$, $TS(I)$ ARE ORDERED PAIRS CORRESPONDING TO TIME (SEC) AND
 $VV(I)$, $XI(I)$, $TS(I)$ ARE ORDERED PAIRS CORRESPONDING TO TIME (SEC) AND
 EY = EXPONENTIAL VOLTAGE DATA (MA) AT ZERO TIME AND SHOULD BE A NOMINALLY INCREASING
 $XI(I)$, $TS(I)$ ORDERED PAIRS CONSISTING OF THE SQUARE ROOT OF
 XI^2 AND CURRENT DATA (MA), AND SHOULD BE ZERO AT
 $XI(0)$ AND $XI(N_{DATA})$ AT INFINITE TIME
 $COMMON/X(2:N_{DATA})$, $Y(0:N_{DATA})$, $XSV(4000)$, $XI(200)$, $TS(200)$, $F(200)$, RZ ,
 $COMMON/A(1:N_{DATA})$, $C(1:N_{DATA})$, $G(1:N_{DATA})$, $P(1:N_{DATA})$, $X(1:N_{DATA})$, $P(1:N_{DATA})$,
 $COMMON/2/NP(2:N_{DATA})$, $VH(1:N_{DATA})$, $XW(1:N_{DATA})$, VFF
 $COMPLEX/ZM(1:N_{DATA})$, $WNP(1:N_{DATA})$, $WPK(1:N_{DATA})$, $WINC(1:N_{DATA})$, $WFIN(1:N_{DATA})$, $U(1:N_{DATA})$, $C(1:N_{DATA})$, $I(1:N_{DATA})$, $O(1:N_{DATA})$, $ZM(1:N_{DATA})$
 EQV = EQUIVALENCE (0RS, ZM)
 $DATA$ = WINIT, WINC, WPK, WINC, WFIN, U, I, O, C, ZM
 $SWITCH=1$ GIVES IMPEDANCE CALCULATION ONLY
 $SWITCH=2$ GIVES IMPEDANCE CALCULATION AND FIT TO MODEL
 $SWITCH=3$ SHUTS DOWN
 $READ(5,*,2)(C1, MPROB, NDATAV, TSAEP, AMPV, FILTC, FILTV$
 $IF(EOP,*,1000,301)$
 $CONTINUE$
 $WRITE(6,*,'0CCCC')$, MPPOR
 $WRITE(6,*,'0CCCC')$, TS
 $WRITE(6,*,'0CCCC')$, TSAEP, FILTC
 $AMPV, AMPF$
 $FILTC$
 $FUAD(5,2,0,0,0)$, $TSV(I,I)$, $VV(I,I)$, $I=1,NDATV$
 $RVAD(5,2,0,0,0)$, $XI(I,I)$, $XI(1,1)$, $I=1,NDATV$
 $WRITET(6,*,'0CCCC')$
 $DO 302 J=1,NDATV$
 $WRITET(6,*,'0CCCC')$, J , $VV(J,J)$, $TSV(J,J)$
 $VV(J,J)=AV(VV(J,J))$
 $+SY(VV(J,J))$
 $302 J=1,NDATV$
 $WRITET(6,*,'0CCCC')$, J , $XI(J,J)$, $TSI(J,J)$
 END

```

206      TSI(J)=TSI(J)*J*J*(1-EX)*(1-EX*(-TSI(J)/TSAEP))
210      XI(J)=XI(J)-AMP1*(1-EX)*(1-EX*(-TSI(J)/TSAEP))
223      HQITE(6,700)
230      N=N+1
233      X(N)=WINI*(N-1)*WINC1
237      NY=N-1
241      X(N)=X(INN)+WINC2
246      CONTINUE
250      H=1.0/(X(N)+*2)
252      F(N)=H*(2*3*141592654)
254      P=CMPPLX(X,W)
255      CALL LPXFRE(MDATA,V,TSV,VY,W,VW)
256      CALL LPXFRE(MDATA,TSI,XI,W,XIW)
257      ADD ZERO FREQUENCY COMPONENT TO TRANSFORM
263      VH=AMPV/P-VW
264      CALL AMP1/(P+(*1+P*TSAEP)) * XIW
265      COMPUTE INVERSE FILTER FUNCTIONS
271      XF=CMPLX(1.0,W*FILT)
272      VF=CMPLX(1.0,W*FILT)
273      ZM(N)=(VW*VF)/(XIW*XF)
274      TF((X(N))/GE.*WFIN-WINC2) GO TO 401
275      GO TO 325
280      CONTINUE
285      WRITE(6,6008)
290      WRITE(6,700)
295      WRITE(6,6009)
300      DO 420 I=1,N
305      I=I+1
310      I2=I+1
315      WRITE(6,6010) I,X(I),03S(I1),08S(I2),F(I)
320      CONTINUE
325      C0F(SWITCH,EN,0.) GO TO 300
330      READ(5,202) A1,S1,C1,A2,S2,C2,R2
334      NE2*N
335      CALL GAULL
336      NPROB=1
337      CALL GAUHH
338      GO TO 300
339      CONTINUE
340      STOP
341      FORMAT(3I5,5F10.5)
342      2002 FORMAT(7F10.5)
343      2003 FORMAT(8F10.5)
344      6000 FORMAT(1X,1S,1F10.5)
345      6001 FORMAT(1X,1S,1F10.5)
346      6002 FORMAT(1X,1S,1F10.5)
347      6003 * T=F10.5 *(SECOND)
348      6003 * FORMAT(5X,1VOLTAGEL7X,(CURRENT CHANGE AT LONG T
349      6003 * YES IS 1.0.5)
350      6004 FORMAT(5X,1INPUT DATA VOLTAGE 7X,(SQRT TIME())
351      6005 FORMAT(15X,1INPUT DATA VOLTAGE 7X,(SQRT TIME())
352      6006 FORMAT(5X,1INPUT DATA CURRENT 7X,(SQRT TIME())
353      6007 FORMAT(10X,1INPUT DATA VOLTAGE 7X,(SQRT TIME())

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6008 FORMAT(1X, [IMPEDANCE DATA])
6009 FORMAT(8X,[DATA POINT],1X,[1/SQRT(OMEGA)],7X,[REAL Z],13X,[IMAGINA G]
6010 *RYZC8X[FREQUENCY(HZ)]
6010 FORMAT(10X,15,4(4X,F14.6))
7000 FORMAT(1X)
ENC

465

PROGRAM LENGTH INCLUDING I/O BUFFERS
000745

FUNCTION ASSIGNMENTS

STATEMENT	ASSIGNMENTS	361	-	00033	320	-	000231	360	-	000267
300	-	00034	-	000435	4000	-	000464	2004	-	000506
401	-	000357	4301	-	000513	6000	-	000515	-	000517
2002	-	000511	2003	-	000536	6004	-	000547	-	000557
6002	-	000524	6003	-	000567	6008	-	000573	-	000577
6006	-	000561	6007	-	000615	-	-	-	-	-
6010	-	000611	7000	-	-	-	-	-	-	-
BLOCK NAMES AND LENGTHS										
SAEP	-	000745	-	012742	A	-	001446	2	-	000010
VARIABLE ASSIGNMENTS										
AMPI	-	000670	AMPV	-	000667	A1	-	000000502	A2	-
C1	-	000602	C2	-	0006512	F	-	0012431501	FILTC	-
FILT	-	000672	T1	-	000673	T1	-	0000677501	T2ATI	-
J	-	000674	MPROB	-	000663	N	-	0000000501	NDATI	-
NDATV	-	000664	NN	-	000675	NPROB	-	0000000503	OBS	-
P	-	000647	PEFS	-	000600000003	RZ	-	00012741501	SWTCH	-
S1	-	0001502	S2	-	00004502	TSAEP	-	0000006601	TSWI	-
TSV	-	00031502	VFFF	-	0000653	VY	-	0000006502	VHINC1	-
W	-	000676	WBPK	-	000657	WFIN	-	0000661501	XFF	-
W1NC2	-	000620	WINIT	-	000655	X	-	0000651501	YHD	-
X1	-	000620	XIN	-	000645	X	-	0000651501	Z	-
ZM	-	00031501	-	-	-	-	-	-	-	-
START OF CONSTANTS										
000470										
START OF TEMPORARIES										
000617										
START OF INDIRECTS										
000635										
UNUSED COMPILER SPACE										
007400										

17 SUBROUTINE MODEL(NPROB,0,6,NG,NQ),YMD(800),XSC(4000),F(200),RZ,TSI(200),
COMMON/A1,S1,C1,A2,S2,VV,W2,ZC1,ZC2,Z1,Z2,G
DCMPLX(X,ZW1,W2,ZC1,ZC2,Z1,Z2,G
COMPLEX X,CTANH
DATA UR,UI/1.,0.,0.,0./

```

S1=Q(1)
A1=Q(2)
C1=Q(3)
A2=Q(4)
S2=Q(5)
RZ=Q(6)
N3=2=NG/2
N3=120/I=1,NG2
XX=X(I)
7C1=-UT*XX**2/C1
ZW1=S1*XX*(1-UI)*CTANH(A1*CSQRT(U1)/XX)
Z1=ZC1*ZW1/(C1+ZW1)
72=92*EQ.0.) GO TO 110
7C2=-UT*XX**2/C2
ZW2=S2*XX*(1-UI)*CTANH(A2*CSQRT(U1)/XX)
Z2=ZC2*ZW2/(C2+ZW1)
110 CONTINUE
111 GCONT=Z1+Z2+R7
120 RETURN
END

```

112 113 114 115 116 117 118 119 120 121 122 123 124 125 126 127 128 129 130 131 132 133 134 135 136 137 138 139 140 141 142 143 144 145 146 147 148 149 150 151 152 153 154 155 156 157 158 159 160 161 162 163 164 165 166 167 168 169 170 171 172 173 174 175 176 177 178 179 180 181 182 183 184 185 186 187 188 189 190 191 192 193 194 195 196 197 198 199 200 201 202 203 204 205 206 207 208 209 210 211 212

SUBPROGRAM LENGTHS

000303

FUNCTION ASSIGNMENTS

STATEMENT ASSIGNMENTS
110 - 000201

BLOCK NAMES AND LENGTHS
MODEL - 000303 - 012742 A - 001446

VARIABLE ASSIGNMENTS	-	000003S12	CTANH	-	000276	C1	-	00002S62
A1	-	000005S02	A2	-	000301	NG2	-	0001S12
C2	-	000005S02	RZ	-	000274	S02	-	000272
Q85	-	000341S02	TSI	-	000629	S01	-	000271S01
TSI	-	000413S02	X	-	000262	ZC2	-	0002673
VV	-	000006S02	Y10	-	000626	Z1	-	000000
XX	-	000003S02	ZH2	-	000266	ZZ	-	000000
ZW1	-	000003S02	ZH2	-	000266	ZZ	-	000000

START OF CONSTANTS
000215

210
211 22222222222222222222

6 A2
66666666666666666666
SUBROUTINE PARTIAL(NGD0,NG,NG0)
COMMON N,X(2C),OBS(40),YMD(800),XS(4000),F(200),R2
DIMENSION I(1),NGD0(NG,NG),NO
DO 120 I=1,NO
P=PS12=.5/PEPS(I)
QSAVE=Q(I)
Q(I)=QSAVE+PEPS(I)
CALL MODEL(NPROB,I,NGD0(I,I),NG,NG,NO)
CALL = QSAVE-PEPS(I)
CALL MODEL(NPROB,0,YMD(1),NG,NG)
Q(I)=QSAVE
DO 120 J=1,NG
DO 120 J=1,NG
CONTINUE=(NGD0(J,I)-(NGD0(J,I)-YMD(J)))*PEPS12
120 RETURN
FNC

SUBPROGRAM LENGTH
000105

FUNCTION ASSIGNMENTS

STATEMENT ASSIGNMENTS

BLOCK NAMES AND LENGTHS

VARIABLE	ASSIGNMENTS	-	012742	2	-	000010
O3S	012431S01 I	=	000101	JPEPS12	-	000104
X	000311S01 PEPS	=	0002571S12	YMD	-	000102
	0000311S01 XS	-	002571S12	-	-	001131S11

START OF CONSTANTS

000067
SIAPT OF TEMPORARIES

000071
START OF INDIRECTS
000075

UNUSED COMPILER SPACE
011200

```

COMPLEX FUNCTION CTANH(Z)
COMPLEX UI,7
DATA UI/0.1618/1./60.1/
TF(CABS(Z).GT.1.0)
CTANH=-UI*COS(UI*Z)/COS(UI*Z)
RETURN
TF(CABS(Z).GT.39.1)
CTANH=(1.-CEXP(-Z)).*Z)
T0=1.+CEXP(-Z.*Z))
1      RETURN
CONTINUE
2      CTANH=CMPLX(1.,0.)
RETURN
END

```

SUBPROGRAM LENGTH 000143	FUNCTION ASSIGNMENTS STATEMENT ASSIGNMENTS 1 - 000047 2 - 0	BLOCK NAMES AND LENGTHS CTANH - 000143	VARIABLE ASSIGNMENTS UI CTANH - 000137	START OF CONSTANTS 000115	START OF TEMPORARIES 000123	START OF INDIRECTS 000137	UNUSED COMPILER SPACE 011200
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SUBROUTINE IXFORM(INDAT,T,YTM,WY)
C THIS SUBROUTINE COMPUTES THE WY PLACE TRANSFORM AT ANGULAR FREQUENCY
C OF THE SET OF ORDERED PAIRS T AND VT CORRESPONDING TO TIME AND
C FUNCTION VALUE AT THAT TIME. THE WY APPROACH ZERO AT INFINITE TIME AND CANNOT CROSS ZERO.
C DIMENSION T(200),VT(200)
C COMPLEX YTM,CA,CI,CIP,CQ1,C11,CIP1
C YTM=ENDAT-1
C DO 104 I=1,IN
C     IP=(VT(I)-E0*A)/C1
C     VT(I)=0.00001
C     IF((VT(I)) .LT. 0.0) GO TO 150
C     VT(I)=VT(I)/VT(I)
C     VT(I)=ALOG((VT(I))/VT(I))/(I-T(IP))
C     CA=CMPLEX(C0,-WT(I))
C     CTIP=CMPLEX(C0,-WT(T(I))*CEXP(CIP))
C     VTW=YTM+(VT(I)*CTIP)-VT(T(I))/CA
C     GO TO 100
C 104 IF((T(I)-TIP).LT.0.0) T(I)=0.00001
C     DT=(VT(I)-DT)*VT(I)/(1-DT)
C     B=(VT(I)-B)/VT(I)
C     CA=CMPLEX(C0,-WT(I))
C     CI=CEXP(-CA*T(I))/CA
C     CIP1=CEXP(-CA1*T(IP))/CA1
C     VTW=YTM+A*(CI*(T(I)+1./CA1)-CIP1*(T(IP)+1./CA1))+B*(C11-CIP1)
C     CONTINUE
C     VTW=VTW+VT(IP)*CEXP(CIP)/CA
C     RETURN
END

```

SUBPROGRAM LENGTH	000420
FUNCTION ASSIGNMENTS	
STATEMENT ASSIGNMENTS	
100 - 000255 101 - 000312 150 - 000122	
BLOCK NAMES AND LENGTHS	
LPXFRM - 000420	
VARIABLE ASSIGNMENTS	
A - E00415 A	= 000417 CA = 000376 C41 = 000410 C11 = 000412 IP = 000413 IM = 000414
CI - E00406 CIP = 000402 CI = 000410	
DI - 000416 I	
START OF CONSTANTS	
000315	

